# An Estimation of Ti and Ni Calibration X-rays Yields by GEANT4 Simulation 

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## 1 Introduction

Ti and Ni X-rays are used for energy calibration at E570. It is necessary to decide these foils positions and sizes. In order to avoid attenuating Kaonic Helium X-ray by foils, the position is limited, upstream target cell Mylar, downstream target cell Mylar glue point and/or the center of SDD support. We estimated reasonable points by GEANT4 simulation.

## 2 Geometry

Simulation geometry is shown on Fig.1, 2, 3. $z$ axis is beam direction and $z=0$ is target center. Fig. 1 is $z=75 \mathrm{~mm}$ Mylar glue point simulation. $y>0$ higher half circle is Ni foil and $y<0$ lower half circle is Ti foil. Fig. 2 is $z=-75 \mathrm{~mm}$ upstream Mylar backside simulation. Fig. 3 is cone foils simulation at $z=133 \mathrm{~mm}$. X-rays are shot only on these foils with the distribution of $\pi^{-}$profile. This means when charged particles (mainly $\pi^{-}$) hit foils, always X-rays are radiated, but now $\pi^{-}$is virtual and only X-ray is shot.

Some X-rays are detected by SDDs (orange boxes), so from the detected number ratio of radiated X-rays and shot X-rays, the attenuation effect and solid angle efficiency is measured. Next by the normalization for K-shell ionization cross sections, true X-rays yields are calculated.

## 3 Simulation

## $3.1 z=75 \mathrm{~mm} 500,000$ beamOn

On the Fig. 1 geometry 500,000 X-rays are shot. X-rays are distributed $\pi^{-}$profile gaussian ( $x$ and $y$ direction) at this point. Results are shown in Table.1.

### 3.2 Normalization

### 3.2.1 Ni X-ray Case

Radiated X-rays number $N$ is

$$
\begin{equation*}
N=N_{\text {obs }} / \text { efficiency }=\left(\text { through } \pi^{-}\right) \times \sigma_{K}\left[\mathrm{~cm}^{2}\right] \times \omega_{K} \times N_{A} \times \frac{8.91\left[\mathrm{~g} / \mathrm{cm}^{3}\right]}{58.70[\mathrm{~g} / \mathrm{mol}]} \times 10^{-3}[\mathrm{~cm}] \tag{1}
\end{equation*}
$$



Fig. $1 \quad z=75 \mathrm{~mm}$ Mylar glue point simulation. 50 particles are "beamOn"ed, three X-rays are radiated (can see only two).


Fig. $2 \quad z=-75 \mathrm{~mm}$ upstream Mylar backside simulation. However many $\pi^{-}$hit these half disc foils and many X-rays are radiated, only few X-rays reach SDDs because of large attenuation.


Fig. $3 \quad z=133 \mathrm{~mm}$ cone foils simulation. To avoid attenuating Kanoic Helium X-rays and to cover solid angle for SDDs, foils are tilted. This position is most reasonable for $\pi^{-}$inducing.

Table. 1 The Number of X-rays detected by 6 SDDs at $z=75 \mathrm{~mm}$ and the number of X-rays radiated ( $=$ through $\pi^{-}$). And total efficiency of detection (attenuation, solid angle).

| X-ray | through $\pi^{-}$ | observed X-ray | total efficiency (\%) |
| :---: | ---: | ---: | :---: |
| Ni | 24039 | 82 | 0.3411 |
| Ti | 28183 | 118 | 0.4187 |
| Other |  | 2 |  |

Where $\sigma_{K}$ is K-shell ionization cross section, $\omega_{K}$ is K-fluorescence yield, $N_{A}$ is Avogadro's number. $\sigma_{K}$ is calculated from the data of E549 test, so $\sigma_{K}=232.974 \pm 12.053 \mathrm{barn}$, and $\omega_{K}=0.414$, through $\pi^{-}=$ 24039 are substituted,

$$
\begin{align*}
N & =(232.974 \pm 12.053) \times 10^{-24} \times 24039 \times 0.414 \times 6.02 \times 10^{23} \times \frac{8.91}{58.70} \times 10^{-3} \\
& =211.866 \pm 10.961 \tag{2}
\end{align*}
$$

then detection efficiency is considered,

$$
\begin{equation*}
N_{\mathrm{obs}}=(211.866 \pm 10.961) \times 0.003411=0.722675 \pm 0.037388 \tag{3}
\end{equation*}
$$

And the total $\pi^{-}$number is 1212568 [counts/spill], times the ratio,

$$
\begin{equation*}
N_{\mathrm{obs}}=(0.722675 \pm 0.037388) \times 1212568 / 500000=1.75256 \pm 0.09067[\text { counts } / \mathrm{spill}] \tag{4}
\end{equation*}
$$

This means Ni Ka X-ray will be detected 1.75 [counts/spill].

### 3.2.2 Ti X-ray Case

Radiated X-rays number $N$ is

$$
\begin{equation*}
N=N_{\text {obs }} / \text { efficiency }=\left(\text { through } \pi^{-}\right) \times \sigma_{K}\left[\mathrm{~cm}^{2}\right] \times \omega_{K} \times N_{A} \times \frac{4.54\left[\mathrm{~g} / \mathrm{cm}^{3}\right]}{47.867[\mathrm{~g} / \mathrm{mol}]} \times 10^{-3}[\mathrm{~cm}] \tag{5}
\end{equation*}
$$

This time $\sigma_{K}=561.376 \pm 82.202$ barn, and $\omega_{K}=0.219$, through $\pi^{-}=24039$ are substituted,

$$
\begin{align*}
N & =(561.376 \pm 82.202) \times 10^{-24} \times 24039 \times 0.219 \times 6.02 \times 10^{23} \times \frac{4.54}{47.867} \times 10^{-3} \\
& =168.745 \pm 28.969 \tag{6}
\end{align*}
$$

then detection efficiency is considered,

$$
\begin{equation*}
N_{\text {obs }}=(168.745 \pm 28.969) \times 0.004187=0.706535 \pm 0.121293 \tag{7}
\end{equation*}
$$

And the total $\pi^{-}$number is 1212568 [counts/spill], times the ratio,

$$
\begin{equation*}
N_{\text {obs }}=(0.706535 \pm 0.121293) \times 1212568 / 500000=1.71344 \pm 0.29415[\text { counts } / \text { spill }] \tag{8}
\end{equation*}
$$

This means Ti Ka X-ray will be detected 1.71 [counts/spill] (but it's error is large).

## $3.3 z=-75 \mathrm{~mm} 500,000$ beamOn

On the Fig. 2 geometry 500,000 X-rays are shot. X-rays are distributed $\pi^{-}$profile gaussian ( $x$ and $y$ direction) at this point. Results are shown in Table.2.

Table. 2 The Number of X-rays detected by 6 SDDs at $z=-75 \mathrm{~mm}$ and the number of X-rays radiated ( $=$ through $\pi^{-}$). And total efficiency of detection (attenuation, solid angle).

| X-ray | through $\pi^{-}$ | observed X-ray | total efficiency (\%) |
| :---: | ---: | ---: | :---: |
| Ni | 233805 | 147 | 0.06287 |
| Ti | 255524 | 53 | 0.02074 |
| Other |  | 2 |  |

### 3.4 Normalization

### 3.4.1 Ni X-ray Case

Calculate same as before... Radiated X-rays number $N$ is

$$
\begin{align*}
N & =(232.974 \pm 12.053) \times 10^{-24} \times 233805 \times 0.414 \times 6.02 \times 10^{23} \times \frac{8.91}{58.70} \times 10^{-3} \\
& =2060.62 \pm 106.61 \tag{9}
\end{align*}
$$

then detection efficiency is considered,

$$
\begin{equation*}
N_{\text {obs }}=(2060.62 \pm 106.61) \times 0.0006287=1.29551 \pm 0.067024 \tag{10}
\end{equation*}
$$

And the total $\pi^{-}$number is 1267934 [counts/spill], times the ratio,

$$
\begin{equation*}
N_{\text {obs }}=(1.29551 \pm 0.067024) \times 1267934 / 500000=3.28525 \pm 0.17000 \text { [counts/spill] } \tag{11}
\end{equation*}
$$

This means Ni Ka X-ray will be detected 3.28 [counts/spill].

### 3.4.2 Ti X-ray Case

Radiated X-rays number $N$ is This time $\sigma_{K}=561.376 \pm 82.202$ barn, and $\omega_{K}=0.219$, through $\pi^{-}=$ 255524 are substituted,

$$
\begin{align*}
N & =(561.376 \pm 82.202) \times 10^{-24} \times 255524 \times 0.219 \times 6.02 \times 10^{23} \times \frac{4.54}{47.867} \times 10^{-3} \\
& =1793.68 \pm 262.25 \tag{12}
\end{align*}
$$

then detection efficiency is considered,

$$
\begin{equation*}
N_{\text {obs }}=(1793.68 \pm 262.25) \times 0.0002074=0.372010 \pm 0.054473 \tag{13}
\end{equation*}
$$

And the total $\pi^{-}$number is 1267934 [counts/spill], times the ratio,

$$
\begin{equation*}
N_{\text {obs }}=(0.372010 \pm 0.054473) \times 1267934 / 500000=0.943368 \pm 0.138137 \text { [counts/spill] } \tag{14}
\end{equation*}
$$

This means Ti Ka X-ray will be detected 0.94 [counts/spill].

## $3.5 z=133 \mathrm{~mm} 500,000$ beamOn

On the Fig. 3 geometry 500,000 X-rays are shot. X-rays are distributed $\pi^{-}$profile gaussian ( $x$ and $y$ direction) at this point. Results are shown in Table.3.

Table. 3 The Number of X-rays detected by 6 SDDs at $z=133 \mathrm{~mm}$ and the number of X-rays radiated ( $=$ through $\pi^{-}$). And total efficiency of detection (attenuation, solid angle).

| X-ray | through $\pi^{-}$ | observed X-ray | total efficiency (\%) |
| :---: | ---: | ---: | :---: |
| Ni | 35726 | 99 | 0.277109 |
| Ti | 37330 | 89 | 0.238414 |
| Other |  | 3 |  |

### 3.6 Normalization

### 3.6.1 Ni X-ray Case

Calculate same as before... the total $\pi^{-}$number is 1186434 [counts/spill] at $z=133 \mathrm{~mm}$, so

$$
\begin{equation*}
\left.N_{\text {obs }}=(314.868 \pm 16.2898) \times 0.00277109 \times 1186434 / 500000=2.07039 \pm 0.10711 \text { [counts } / \text { spill }\right] \tag{15}
\end{equation*}
$$

This means Ni Ka X-ray will be detected 2.07 [counts/spill].

### 3.6.2 Ti X-ray Case

$$
\begin{equation*}
N_{\mathrm{obs}}=(262.043 \pm 38.3708) \times 0.0002074=0.372010 \pm 0.054473 \tag{16}
\end{equation*}
$$

And the total $\pi^{-}$number is 1267934 [counts/spill], times the ratio,

$$
\begin{equation*}
N_{\text {obs }}=(262.043 \pm 38.3708) \times 0.00238414 \times 1186434 / 500000=1.48244 \pm 0.21707 \text { [counts/spill] } \tag{17}
\end{equation*}
$$

This means Ti Ka X-ray will be detected 1.48 [counts/spill].

## 4 Conclusion

Simulation results summarized on Table. 4 .
Table. 4 The summary of simulation results.

|  | $z=75$ circle | $z=-75$ disc | $z=133$ cone | total |
| :--- | :---: | :---: | :---: | :---: |
| Ni [counts/spill] | 1.753 | 3.285 | 2.070 | 7.108 |
| Ti [counts/spill] | 1.713 | 0.9434 | 1.482 | 4.138 |
| Foil area $\left[\mathrm{cm}^{2}\right]$ | 100 | 314 | 31.5 | 445.5 |

If all foils are used, $\mathrm{Ni} \mathrm{K}_{\alpha}$ X-ray can be seen 7.108 [counts/spill] and $\mathrm{Ti} \mathrm{K}_{\alpha}$ X-ray can be seen 4.138 [counts/spill]. But at $z=-75$ disc foil, Ti X-ray is attenuated by Mylars and target, so it's foil area performance is bad. On the other hand, $z=133$ cone foil has very good foil area performance. This is because, it is recommended that more larger cone foils and downstream Mylar glue point foils are used and not used upstream Mylar disc foil.

The two positions circle and cone foils are enough for energy calibration. The estimated Kaonic Helium X -ray count rate is

$$
\begin{align*}
N_{K^{-} \mathrm{He}}= & 6000\left[\text { Stopped } K^{-}\right] \times \frac{1}{6} \times 0.16 \times \frac{1}{400}[\text { SDD efficiency }] \\
& \times 30 \%[\text { vertex counter solid angle coverage }] \times \frac{3}{4}[\text { DAQ acceptance }]=0.09[\text { counts } / \text { spill }] \tag{18}
\end{align*}
$$

So, calibration X-rays will be seen about 30 times larger than Kaonic Helium X-ray.

## Typical analysis result at a production run

Mn mean has large error $1 \sigma \sim 10 \mathrm{eV}$, because Mn Kb X -ray is low statistic.

500,000 events correspond to 430 spills ( 10 min ).


## Sum run data fitting

## 21628 spills, 9 hours detection

## Ni


$\begin{array}{ll}\text { Mean }=7493.23(\mathrm{eV}) & \text { error }=15.5866 \\ \text { FWHM }=175.486(\mathrm{eV}) & \text { error }=6.28352 \\ \text { Event }=1330.83 \text { (Counts) } & \text { error }=68.85\end{array}$
$\begin{array}{lll}\text { Mean }=4498.6(\mathrm{eV}) & \text { error }=13.0163 \\ \text { FWHM }=147.94(\mathrm{eV}) & \text { error }=16.8941 \\ \text { Event }=387.497(\text { Counts }) & \text { error }=56.7408\end{array}$
Mn Kb's error propagates to X-rays mean, so X-ray mean has large error It is necessary to calibrate from higher statistic peaks

## E570 meeting

## 2005/07/12 S.Okada and H.Tatsuno

## 1 Summary of trigger scheme of SDD test experiment at E549

### 1.1 Trigger logic



Figure 1: Trigger logic diagram for E549 SDD test experiment

### 1.2 Module list

| Module list for test experiment at E549 |  |  |
| :---: | :---: | :---: |
| module | model number | borrowed from ... |
| Shaping amp $(0.5 \mu \mathrm{~s})$ | ORTEC $570^{*}$ | Banpaku-san |
| Shaping amp $(2 \mu \mathrm{~s})$ | ORTEC 572 | SKS |
| TAC | ORTEC 467 | Hayano-lab. |
| PH ADC | TKO 32CH PH ADC (T005) | KEK electronics equipment pool |

* These modules have been used in KpX experiment. We have borrowed four ORTEC 570 modules from Banpaku-san.


### 1.3 Timing relation



Figure 2: TDC start and stop timing


Figure 3: ADC gate timing (SDD self trigger)


Figure 4: Summary of SDD timing

### 1.4 Typical SDD count rate



Figure 5: SDD single count rate per spill (without ${ }^{55} \mathrm{Fe}$ source)

## 2 Trigger and DAQ system at E570

### 2.1 Intensity ratio between real kaonic helium x-ray and calibration x-rays

The count numbers (per spill) of Ni and Ti calibration peak estimated by a simulation with real geometry by using measured K-shell ionization and excitation cross sections for minimum ionizing pion are respectively about $2(\mathrm{Ni})$ and $1(\mathrm{Ti})$ counts/spill (for cone type foil). In case these foils are additionally put on the front face of target cell and near side of overlap width part of target cell, the count rate will be increased by 3 times higher at most.

Estimated count rates (per spill) for kaonic helium x-rays , $L_{\alpha}, L_{\beta}$ and $L_{\gamma}$, are as follows.

$$
\begin{aligned}
Y_{K-H e}\left(L_{\alpha}\right)= & 6000(\text { stopped kaon per spill }) \times 1 / 6(\text { stopping ratio for real }) \\
& \times 0.09\left(\text { intensity per stopped kaon for } L_{\alpha}\right) \times 1 / 400(\mathrm{SDD} \text { efficiency }) \\
& \times 0.3(\mathrm{VTC} \text { solid angle }) \times 0.75(\mathrm{DAQ} \text { accept ratio }) \\
= & 0.05[\text { counts } / \text { spill] } \\
Y_{K-H e}\left(L_{\beta}\right)= & 0.03\left[\text { counts } / \text { spill] }\left(L_{\beta} \text { intensity per stopped kaon }=0.05\right)\right. \\
Y_{K-H e}\left(L_{\gamma}\right)= & 0.01\left[\text { counts } / \text { spill] }\left(L_{\gamma} \text { intensity per stopped kaon }=0.02\right)\right.
\end{aligned}
$$

So the Ni and Ti calibration peak intensities will be respectively obtained 40 and 20 times higher than that of real kaonic helium $L_{\alpha}$ peak (without considering DAQ accept ratio) when we take the SDD self trigger events. If we do not take SDD self trigger events in particular, the ratio between the count rate due to accidental coincidence within kaon trigger and real kaonic $L_{\alpha}$ peak rate will be $8 \%$ as follows.

$$
\begin{aligned}
& 2(\text { count } / \text { spill }(\mathrm{Ni})) \times 7 \times 10^{-6}(\sec (\text { ADC gate width })) \\
& \quad \times 500(\text { trigger rate per spill }) / 1.7(\sec (\text { spill period })) / 0.05\left(Y_{K-H e}\left(L_{\alpha}\right)\right)=0.08
\end{aligned}
$$

Even allowing for additional foil $(\times 3)$ and difference of K-shell ionization (excitation) cross section for fast pion and the slow stopping kaon ( $\times \sim 4$ [see T.M.Ito et.al. PRC58, 2366 (1998)]), the ratio will be $24 \times 4 \times\left(R_{1}+R_{2}+R_{3}\right) \%$ at most, where $R_{1,2,3}$ denote kaon stopping ratio at each foil location ( $\sim 50 \%$ ?).

### 2.2 Trigger

- In order to increase as many x-ray events as possible, we plan to take the unbiased " $\mathrm{K}_{\text {stop }} \times \mathrm{VTC} \times$ VDC veto" trigger at E570 instead of taking " $\mathrm{K}_{\text {stop }} \times$ VTC / 10" and " $\mathrm{K}_{\text {stop }} \times$ VTC $\times$ NC" triggers. On the run280 at E549 which is a dedicated run for the study of E570 trigger, we confirmed that by adding "VDC veto" the number of "K $\mathrm{K}_{\text {stop }} \times \mathrm{VTC}$ " trigger is reduced by $65 \%(=790 / 1210)$. In this case, the accept ratio was reduced by $7.6 \%(83.7 \% \rightarrow 75.9 \%)$. (see case 1)
- As shown in Fig.5, SDD single count rate is about 17 per spill if we can cut the overflow events on trigger level (applying upper threshold by another discriminator). The count rate of eight SDDs will be about 150. In case the SDD self trigger ( $\sim$ 150 ) is added as SDD calibration trigger, the accept ratio was reduced by about 3 $\%$ additionally. (see case 2 and 3 )

| Number of trigger per spill |  |  |  |  |
| :---: | :---: | :---: | :---: | :---: |
| Trigger type | E549 normal trig. | E570 trig. |  |  |
|  |  | $\begin{gathered} \text { case 1 } \\ \left(\text { run } 280^{(i)}\right) \end{gathered}$ | $\begin{gathered} \text { case } 2 \\ \text { case } 1+\text { self trig. } \end{gathered}$ | $\begin{gathered} \text { case } 3 \\ \text { E } 549+\text { self trig. } \end{gathered}$ |
| $\mathrm{K}_{\text {stop }} \times$ beam / 600 | 10 | 10 | 10 | 10 |
| $\mathrm{K}_{\text {stop }} \times \mathrm{VTC} / 10$ | 100 | - | - | 100 |
| $\mathrm{K}_{\text {stop }} \times \mathrm{PA} \times \mathrm{PB}$ | 100 | 100 | 100 | 100 |
| $\mathrm{K}_{\text {stop }} \times \mathrm{VTC} \times \mathrm{NC}$ | 340 | - | - | 340 |
| $\mathrm{K}_{\text {stop }} \times \mathrm{VTC} \times \mathrm{VDC}$ veto | - | 790 | 790 | - |
| SDD self trigger | - | - | 150 | 150 |
| total | 550 | 900 | 1050 | 700 |
| accept (calc.) | 461 | 683 | 766 | 561 |
| accept ratio ${ }^{(i)}$ | 83.7 \% | 75.9 \% | 73.0 \% | 80.2 \% |

${ }^{(i)}$ This is a dedicated run for study of E570 trigger at E549.
${ }^{(i i)}$ The accept ratio is determined by the dead time attributed to its DAQ system, which is about $600 \mu \mathrm{sec}$ (TKO conversion time $300 \mu \mathrm{sec}+$ computer busy $300 \mu \mathrm{sec}$ ), and is calculated by the following equation : $m \times T=k+m \times k \times t$, where $m=$ True count rate, $T=$ Counting period, $k=$ Number of count in a time $T$, and $t=$ Dead time. The measured trigger number accepted by DAQ system was consistent with calculated one.

### 2.3 E570 trigger system

### 2.3.1 Conventional method



Figure 6: Trigger logic diagram for E570 (conventional method)

| Module list for E570 |  |  |  |
| :---: | :---: | :---: | :---: |
| module | model number | number | will be borrowed from $\ldots$ |
| Shaping amp $(0.5,2 \mu \mathrm{~s})$ | ORTEC 570 | $\times 16$ | Banpaku-san |
| PH ADC | TKO 32CH PH ADC | $\times 1$ | KEK |
| TDC | TKO 16CH HR TDC | $\times 1$ | KEK (ask Sasaki-san) |


| TAC | ORTEC 566 | $\times 8$ | 393,000JPY (SEIKO EG\&G) |
| :---: | :---: | :---: | :--- |
| TAC | ORTEC 567 | $\times 8$ | 523,000 JPY (SEIKO EG\&G) |

### 2.3.2 with VME TDC and ADC



Figure 7: Trigger logic diagram for E570 with VME TDC and ADC

| Module list for E570 |  |  |  |  |
| :---: | :---: | :---: | :---: | :---: |
| module | model number | number | cost (company) |  |
| NIM spectroscopy amp | CAEN 16 channel programmable <br> spectroscopy amplifier: N568BD | $\times 1$ | $1,277,000 J P Y$ |  |
| (SEIKO EG\&G) |  |  |  |  |$|$| VME TDC | CAEN 16channel <br> multihit TDC: V1290N | $\times 1$ | 825,000 JPY <br> (SEIKO EG\&G) |
| :---: | :---: | :---: | :---: |
| VME ADC | CAEN 16channel multihit <br> peak sensing ADC: V785ND <br> conversion time : $2.8 \mu \mathrm{sec} / 16 \mathrm{ch}$ | $\times 1$ | $768,000 \mathrm{JPY}$ <br> (SEIKO EG\&G) |

## E570 time schedule

|  |  | SDD | Target modification | Temperature control |
| :---: | :---: | :---: | :---: | :---: |
| $7 / 11$ (Mon) - 7/17 (Sun) | Operation check for all our SDDs |  |  |  |
| $7 / 18$ (Mon) - 7/24 (Sun) |  |  |  |  |
| $7 / 25$ (Mon) - 7/31 (Sun) | Preamp test | Three SDDs from SMI will arrive on? (ask Hannes) | end of July : almost all parts will be delivered. |  |
| 8/01 (Mon) - 8/07 (Sun) | Start on target cooling test |  |  |  |
| $8 / 08$ (Mon) - 8/14 (Sun) |  |  | 8/10 $\cdots$ stainless end cap will be delivered. |  |
| $8 / 15$ (Mon) - 8/21 (Sun) |  |  |  | Lakeshore340 / PT-102 will be delivered. |
| $8 / 22$ (Mon) - 8/28 (Sun) |  | Another two SDDs will be delivered from KETEK.(?) |  |  |
| $8 / 29$ (Mon) - 9/04 (Sun) |  |  |  |  |
| 9/05 (Mon) - 9/11 (Sun) |  |  |  |  |
| 9/12 (Mon) - 9/18 (Sun) |  |  |  |  |
| 9/19 (Mon) - 9/25 (Sun) |  |  |  |  |
| 9/26 (Mon)- | from $9 / 27 \cdots$ Beam time |  |  |  |

